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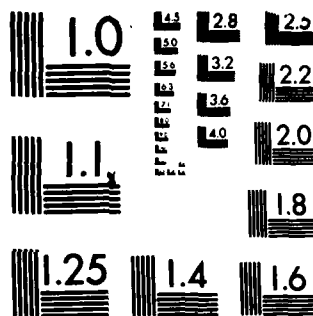
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Multiple Scattering Effects in EXAFS: Comparison between
Theory and Experiment for Pt Metal

by

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**Multiple scattering effects in EXAFS: comparison between
theory and experiment for Pt metal**

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Extended x-ray absorption fine structure (EXAFS) model functions have been calculated for the L_{III} edge in Pt metal. All single, double and triple scattering contributions were taken into account, using a recently developed multiple scattering formalism. Theoretical values for the scattering amplitude, phase, and Debye-Waller factor and the "universal curve" for the electron mean free path have been used. Comparison to experimental data gives an estimate of the limitations in the current formalism, and shows that multiple scattering effects are important in Pt only at radial distances corresponding to fourth shell nearest neighbors.

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I. INTRODUCTION

Extended x-ray-absorption fine-structure (EXAFS) measurements have been used in the extraction of structural information in a variety of materials.¹ The single-scattering formula²

$$\chi(k) = \frac{|\mathcal{F}(\pi, k)|}{k^2} e^{-2\tau/\lambda} e^{-2k^2\sigma^2} \sin[2kr + \phi(\pi, k)] \quad (1)$$

is commonly used to extract information about coordination number, radial distribution, and other relevant parameters. Analysis often involves Fourier-filtering; i. e. the Fourier-transformation of data, filtering out a specific range in the radial distribution and inverse transform of this range. The region commonly used for the inverse transform usually corresponds to the first or second shell of neighbors, since multiple scattering of the electron emitted from the x-ray-absorbing atom is expected at higher radial distances. To use all the data, and to estimate the accuracy of the single scattering equation, it is important to know the effects of multiple scattering. This is specially true in the case of metal structures, since one of the major applications of EXAFS-studies is to small metal clusters in supported catalysts. Recent work has been reported on three-atom molecules in which multiple scattering effects were used for bond-angle determinations.^{3,4,5} Multiple scattering effects due to the shadowing effect on the fourth nearest neighbors by the second neighbors in metals with fcc structure have been recognized.⁶ A detailed analysis of these effects has not been carried out, partly because theories on multiple scattering effects were not complete.

The present paper examines the importance of multiple scattering and gives an estimate of the accuracy of theoretical calculations. All double scattering contributions to EXAFS are calculated for Pt metal using the

multiple scattering formalism introduced by Lee and Pendry,⁶ and later developed by Teo³ and by Boland et al.⁷ Also, all triple scattering contributions are determined where the total scattering path length does not exceed that of fourth shell single scattering. Comparison of the calculated EXAFS function with the measured L_{III} edge of Pt metal gives an estimate of the photoelectron energy range over which EXAFS theories are applicable. Good agreement is found at energies higher than 50 eV above absorption threshold, which shows the limitation of the theories used.

We used unpublished angle dependent phase and amplitude functions calculated by Teo⁸ using the programs described previously.^{3,9} Published values of these quantities are given only to $k > 4$ because approximations made in their derivation are expected to cause progressively greater inaccuracy at low energies. We used Teo's calculated values down to $k=0.94 \text{ \AA}^{-1}$ and extrapolated to $k=0 \text{ \AA}^{-1}$ in order to test the multiple scattering theory and calculated quantities over the full range of k . As expected, the calculated EXAFS function becomes less accurate at low energies.

II. THEORY

The multiple scattering expressions for the EXAFS given by Teo⁶ and Boland et al.⁷ differ only by the presence of a geometrical factor in the double scattering term. We adopt the form that includes it,⁷ which, in the case of a polycrystalline sample, is given by:

$$\begin{aligned} \chi(k) = & - \sum_{n=1,j} \left\{ \frac{|f_n(\pi, k)|}{kr_n^2} \sin[2kr_n + 2\delta_n(k) + \phi_n(\pi, k)] \right. \\ & + \frac{2f_1 f_j}{kr_1 r_j r_{1j}} |f_1(\beta, k)| |f_j(\alpha, k)| \sin[k(r_1 + r_j + r_{1j}) + 2\delta_k(k) + \phi_1(\beta, k) + \phi_j(\alpha, k)] \\ & \left. + \frac{|f_1(\pi, k)| |f_j(\alpha, k)|^2}{kr_j^2 r_{1j}^2} \sin[2k(r_j + r_{1j}) + 2\delta_k(k) + \phi_1(\pi, k) + 2\phi_j(\alpha, k)] \right\} \quad (2) \end{aligned}$$

where the symbols have the usual meanings: $k=[2m(E-E_0)/\hbar^2]^{1/2}$ is the photoelectron wave vector; $|f(\alpha, k)|$ the scattering amplitude; $\phi(\alpha, k)$ the scattering phase shift, and δ_{ℓ} the phase shift due to the central atom potential. The first term is the usual single scattering expression, whereas the second term corresponds to consecutive scattering by atoms i and j , and vice versa. The third term is the result of photoelectron scattering from atom j to atom i , and back to atom j again. To account for inelastic losses of electrons we multiply each scattering path by $\exp(r/\lambda)$, where λ is the electron mean free path and r the total electron path length. A further correction due to thermal vibrations is the inclusion of the Debye-Waller factor $\exp(-2k^2 \sigma^2)$, with the mean squared displacement σ^2 dependent on the specific scattering path.

The scattering amplitude and phase functions used in the equation above, and shown in Figs. 1 and 2 were those calculated by Teo⁸ at twenty different k -values between 0.9449 \AA^{-1} and 15.1178 \AA^{-1} , for scattering angles between 0° to 180° , in 5° steps. These values were manually replotted and interpolated on a 78 point grid.

The Pt L_{III} edge central atom phase shift $\delta_{\ell=2}(k)$ values were those calculated by Teo and Lee⁹, extended to low k -values by inclusion of unpublished calculations.⁸ Although these calculations are based on certain assumptions, excellent agreement has been found with experimentally extracted phase shift data.¹⁰

For the electron mean free path λ the value of 10 \AA was tried at the beginning of this work as a rough estimate. However, much better agreement with experimental data was achieved by using the universal curve¹¹ for λ , which was used in a tabular form with linear interpolation between points in the range $0.9449 \text{ \AA}^{-1} - 15.1178 \text{ \AA}^{-1}$ (Table I). It should be noted that this

approach is not consistent with the derivation of the Debye-Waller factor, where a k -independent mean free path is assumed.¹² Most of the variation in λ is at low energies (below 50 eV) where we might expect some disagreement with experimental data.

Our previous study¹⁰ shows that anharmonic disorder effects in Pt are negligible at 100 K and calculations based on the Debye approximation are in excellent agreement with experimentally determined disorder. The Debye-Waller factor was calculated in this approximation, where the mean square displacement (MSD) is given by^{13,14,15}

$$\sigma_{\infty}^2 = \frac{3\hbar}{M\omega_D} \left[\frac{1}{4} + \left(\frac{T}{\theta_D} \right)^2 \int_0^{\theta_D/T} \frac{x}{e^x - 1} dx \right] \quad (3)$$

Since EXAFS is only sensitive to relative displacements, the mean square relative displacement (MSRD) is given by

$$\sigma^2 = 2 \sigma_{\infty}^2 (1 - \gamma) \quad (4)$$

with the correlation factor γ calculated by:

$$\gamma = \frac{1}{\sigma_{\infty}^2} \frac{3\hbar}{M\omega_D} \left[\frac{1 - \cos(q_D \cdot r)}{2q_D^2 r^2} + \frac{T}{q_D r \theta_D} \int_0^{\theta_D/T} \frac{\sin(q_D r \frac{T}{\theta_D} x)}{e^x - 1} dx \right] \quad (5)$$

where the symbols have the following meaning: θ_D = Debye temperature, $\omega_D = k \theta_D / \hbar$ Debye frequency and $q_D = (6\pi n/v)^{1/3}$ the Debye wavenumber. Since the correlation is dependent on the radius, the MSRD is also dependent on the scattering path. The parameters used are $\theta_D = 240 \text{ K}^{1.6}$, $n/v = 6.62 \times 10^{-28} \text{ m}^{-3}$,¹⁵ $M = 195 \text{ amu}$ with a corresponding $q_D = 1.577 \text{ \AA}^{-1}$. The calculated results are given in Table II.

In Table III all the parameters needed for calculating the EXAFS equation are shown. Each scattering path is listed separately and is labeled in accordance with the nomenclature used by Lee and Pendry.⁶ 1-2-1 indicates a path which goes from the origin to atom j , which is a first shell distance, to first shell atom i , where the distance between j and i is that corresponding to a second shell, and back to the origin. Similarly, 2-1-3 indicates a path from the origin to second shell atom j and then to third shell atom i which is in the first shell of atom j . All the considered triple scattering paths are 1-1-1-1 paths, so they are labeled Ma to Mg, dependent on the scattering path. For each scattering path, Table III gives the scattering angle, the total distance traveled (corrected for thermal expansion at 100 K), and the angle between r_i and r_j . Since there is more than one atom in the different shells, each scattering path has to be multiplied by the number N of different scattering sequences available to the photoelectron. In the case of single scattering, this is just the number of nearest neighbors in the respective shell, whereas in multiple scattering cases many more equivalent scattering paths are possible. Also included in the table (but not in the final calculation) is single scattering by atoms in the fourth shell and the double scattering 1-4-1 and 1-1-4 paths. All these possibilities are nonphysical, since the second shell atoms shadow the fourth shell atoms. For the fourth shell atoms, the operative scattering paths are the 1-1-1-1 paths.

III. CALCULATIONS

The contribution of all the different multiple scattering paths are shown in Fig. 3. The solid line corresponds to the Ma path, multiplied by 0.6 (see Section IV), and is clearly the strongest multiple scattering contribution. Even by adding up the calculated functions from all double

scattering paths, the Ma contribution is still dominant (Fig. 4). The reason for the small amplitude of most of the double and triple scattering paths is the $1/r^2$ dependence of the EXAFS, and also the low values of the backscattering amplitude at high scattering angles. Because the scattering amplitude peaks in the forward direction, a significant contribution from the Ma and Md paths to the EXAFS is expected. All the other triple scattering contributions are orders of magnitude weaker and can be neglected. The Md to Mg paths are only approximations, since the central atom is involved twice, the second time as an ion (ionized when the photon was absorbed), so that the scattering potential and with it the scattering amplitude and phase is expected to be different compared to the non-ionized case. To account for this circumstance, we allow, in modeling the data, the energy threshold E_0 to be different for each scattering path.

IV. RESULTS

The calculated EXAFS functions were compared to experimental data at the Pt L_{III} edge. The complication which arises from the fact that the initial p-state can go to a final state of s or d symmetry is of only minor concern, because it has been shown from theoretical calculations⁹ that transitions to the d final states are generally favored by a factor of 50 over the s final states, so that we can use the above equations with the $l=2$ central atom phase shift. The experimental EXAFS oscillations were isolated by using a cubic spline technique containing three sections. The data were then normalized to the L_{III} component of the smooth absorption background by using the x-ray absorption coefficient parameterization given by McMaster.¹⁷

The limits of the single scattering approximation can be seen by Fourier-filtering the data in r-space and comparing it with the corresponding model function. Figure 5 shows the filtered spectra (k^1 weighting), where the

allowed inverse transform range was successively increased from the radial distance corresponding to the first shell to all the first four shells. There are no multiple scattering effects expected in the radial range up to the third shell (5 Å), except some negligible contributions from the 1-1-1, 1-2-1 and 2-1-1 paths (Table III), and a comparison of the data with the summed single scattering contribution from the first three shells shows excellent agreement (Fig. 5 A-C). When the fourth shell is included in the filtering process, the single scattering approximation is not appropriate and the corresponding single scattering calculation does not model all the features in the data (Fig. 5 D).

The energy threshold was determined by adjusting E_0 until the Fourier-filtered first shell EXAFS gave agreement in the phase with the calculated first shell model function. The E_0 value is 6 eV above the inflection point. In adding up all the contributions from multiple scattering paths, E_0 was shifted to -12 eV for the Ma and Md paths. To get reasonable agreement with experimental data the EXAFS function corresponding to the Ma path had to be multiplied by 0.6, indicating that the forward scattering amplitude is not as strong as the calculated amplitude functions, which also have the greatest inaccuracy in the forward scattering case. All the other contributions were directly added without any further weighting. Figure 6 shows a comparison of the experimental data to the calculated single scattering contribution and to the sum of all the different scattering paths.

To model the whole Pt L_{III} absorption edge, the calculated EXAFS was superimposed on an edge function.¹⁸ The EXAFS spectra with the added edge is broadened by first convolving it with a Lorentzian broadening function whose width is the sum of the inverse lifetimes of the core hole and the excited electron, and then further convolution with a Gaussian broadening function

whose width accounts for the instrumental resolution (2 eV). A resonance at -2.8 eV with a width of 6 eV gives the best agreement to the Pt white line, together with a Lorentzian broadening of the edge by a width of 4 eV (Fig. 7). Together with the appropriately broadened EXAFS oscillations the normalized model function compared to the experimental data is shown in Fig. 8. There is good agreement above 50 eV and at the edge, but disagreement between 0-50 eV.

V. DISCUSSION

The derivation of the multiple scattering formula of Eq. 2 assumed that the photoelectron was at sufficiently high energy (approximately three times the plasma frequency; > 70 eV in Pt) so that the attractive potential of the central atom nucleus became negligible. This may explain in part the disagreement at low photoelectron energy, where the central atom potential strongly affects the excited electron. The theoretical phase and amplitude functions are also in question at low energies. The mean free path increases very rapidly at low energy, as does the Debye-Waller factor. Therefore all the contributions from different scattering paths have very large amplitudes near the edge and, due to the $2kr$ term in the phase, oscillate very rapidly, which results in large changes in the model function from only very small (0.1 eV) changes in threshold energy for certain scattering paths.

At higher energy it was possible to model all the features of the EXAFS spectra. Each small feature could be identified although not always precisely correct in position and amplitude. The three atom scattering path Ma was the most important multiple scattering effect and was clearly recognizable in the EXAFS spectra. This may be of special importance for small metallic clusters (in supported metal catalysts, for example), where the clusters may be so small or so shaped as to give different multiple scattering contributions than the bulk metal. By modeling different structures and sizes

and then comparing them to the experimental data it should be possible to extract structural information directly from the unfiltered oscillations. Figure 6 shows that there are some features in the data which are not present in the calculated spectra with the correct amplitude. This is an indication that even with the multiple scattering approximation used here with its attendant theoretical parameters there are still small but significant differences from experimental data.

VI. CONCLUSION

The effects of multiple scattering in Pt metal are only important in the fourth shell region. Multiple scattering contributions corresponding to second and third shell neighbor distances are very weak and can be neglected. At total scattering distances corresponding to the fourth shell, the major contribution to the EXAFS comes from the forward scattering by the second nearest neighbor and backscattering by the fourth shell. This component was clearly identifiable in the experimental data. Generally good agreement with EXAFS data ($E > 50$ eV) was obtained by using the multiple scattering formalism of Eq. 2 and the theoretical angle dependent phase shifts and scattering amplitudes of Teo.^{3,8}

ACKNOWLEDGMENTS

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TABLE I. Electron Mean Free Path

$k(\text{\AA}^{-1})$	$\lambda (\text{\AA})$
0.9449	100.
1.8897	11.69
2.8346	6.11
3.7795	5.15
4.2519	5.21
4.7243	5.47
5.1967	5.80
5.6692	6.10
6.1416	6.49
6.6140	6.95
7.0865	7.35
7.5589	7.71
8.5038	8.66
9.4486	9.38
10.3935	10.28
11.3384	11.10
12.2832	11.69
13.2281	12.56
14.1729	13.28
15.1178	14.05

TABLE II. Disorder Calculation Results for
Pt Metal at 100 K

$r(\text{\AA})$	$(q_D r)$	σ_∞^2	γ	σ^2
2.773	4.372	1.490	0.3373	1.975
3.922	6.184	1.490	0.1891	2.417
4.805	7.576	1.490	0.1731	2.465
5.546	8.745	1.490	0.1680	2.480

σ^2 and σ_∞^2 in (10^{-3}\AA^2)

TABLE III. Multiple Scattering Parameter for Pt.

A. Single Scattering

Shell	r_{total}^a	σ^2^b	N
1.	5.538	1.97	12
2.	7.832	2.42	6
3.	9.595	2.46	24
4.	11.076	2.48	12

B. Double Scattering

Scattering Path	r_{total}^a	σ^2^b	N	Scattering Angle		θ^c
1-1-1	8.307	3.9	48	120	120	60
1-2-1	9.454	3.9	24	135	135	90
1-1-2	9.454	3.9	48	90	135	45
1-3-1	10.335	3.9	48	150	150	120
1-1-3	10.335	3.9	96	60	150	30
1-4-1	11.076	3.9	12	180	180	180
1-1-4	11.076	3.9	24	0	180	0
1-2-3	11.482	3.9	48	90	145	55
2-1-3	11.482	3.9	48	90	125	35
2-3-1	11.482	3.9	48	145	55	90

C. Triple Scattering

Scattering Path	r_{total}^a	σ^2^b	N	Scattering Angle			θ^c
Ma	11.076	4.455	12	0	180	0	0
Mb	11.076	4.455	24	90	180	90	0
Mc	11.076	4.455	48	120	180	120	0
Md	11.076	4.455	12	180	0	180	180
Me	11.076	4.455	12	180	180	180	0
Mf	11.076	4.455	24	180	120	180	120
Mg	11.076	4.455	24	180	60	180	60

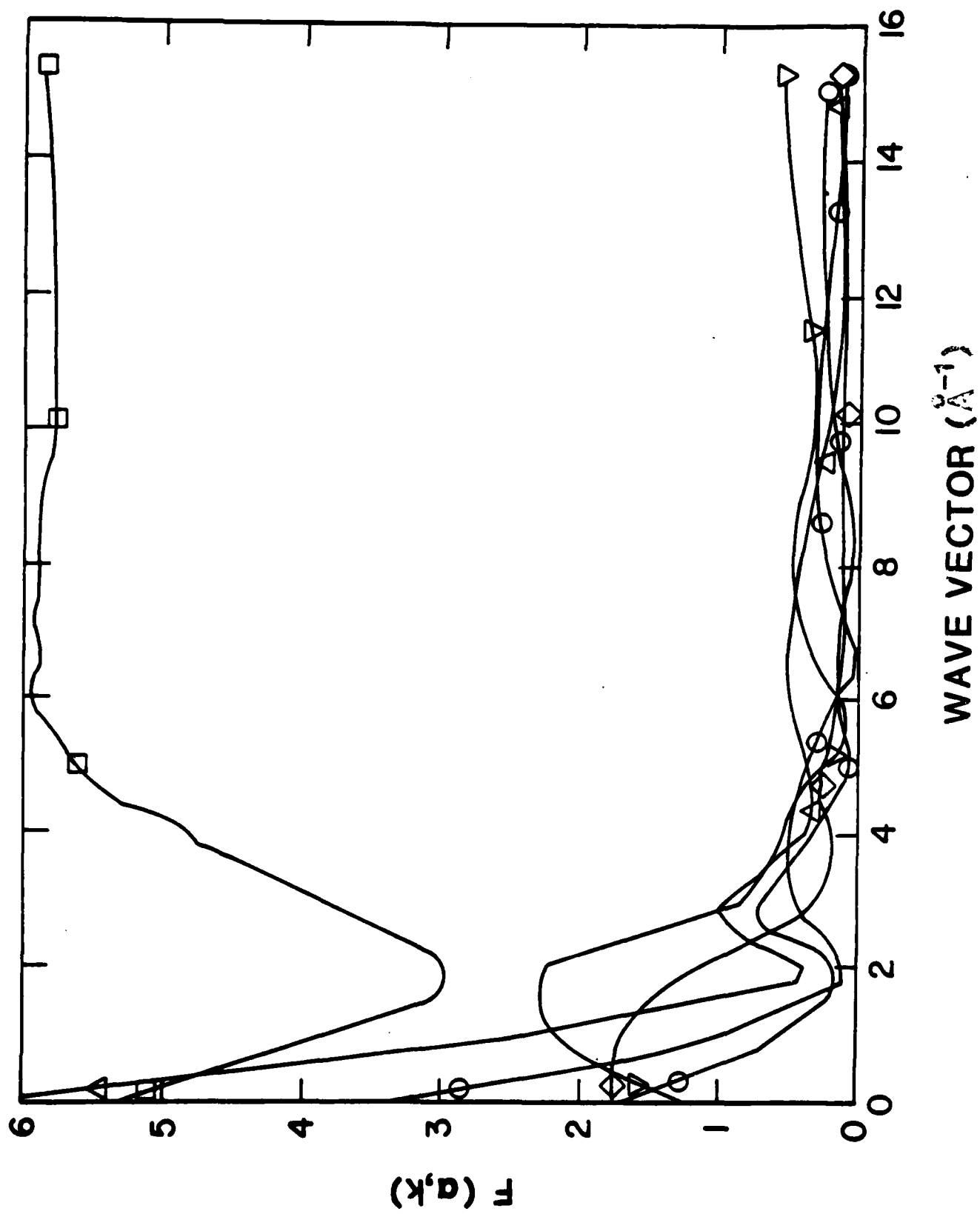
^a r_{total} in (Å)

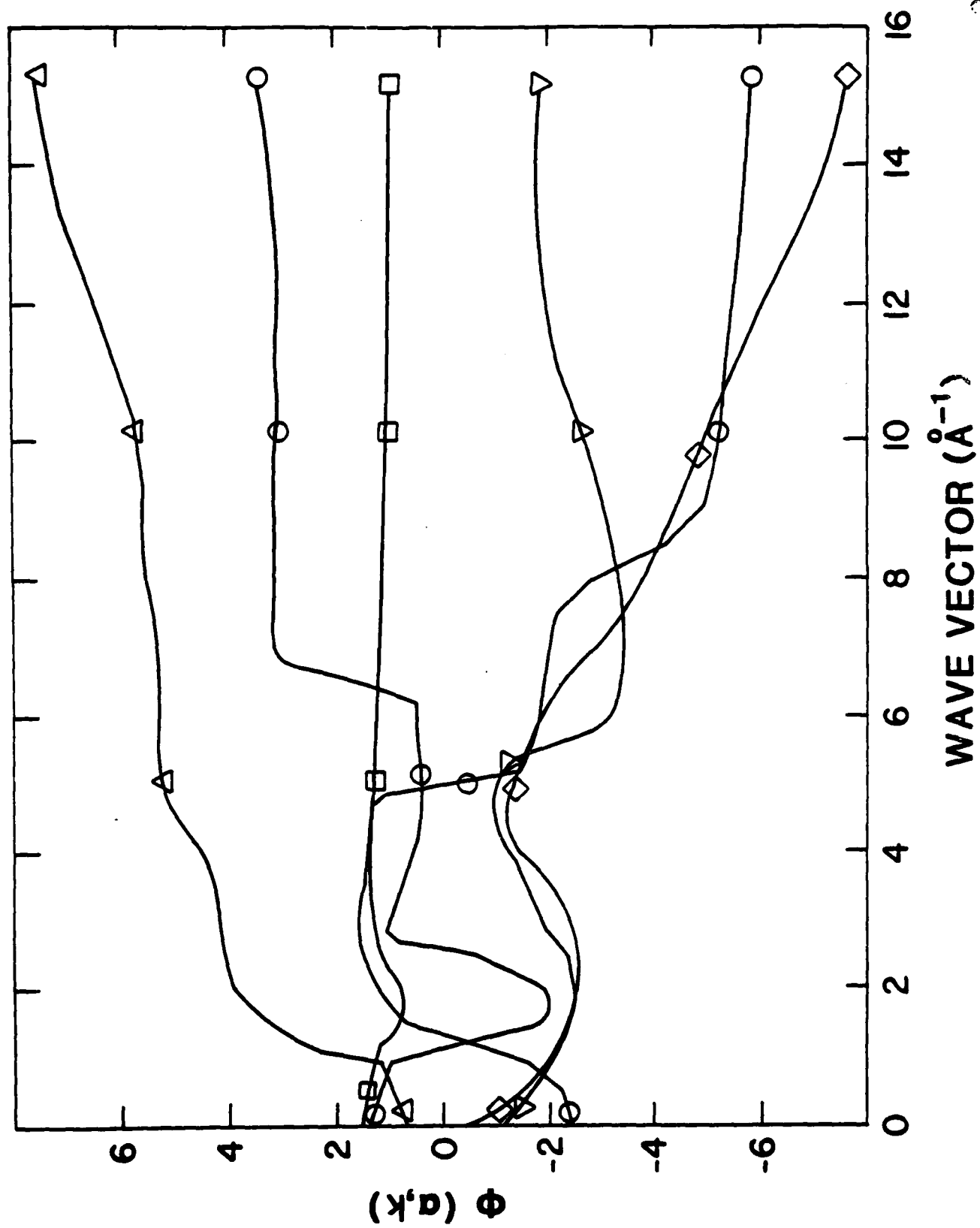
^b σ^2 in (10^{-3}Å^2)

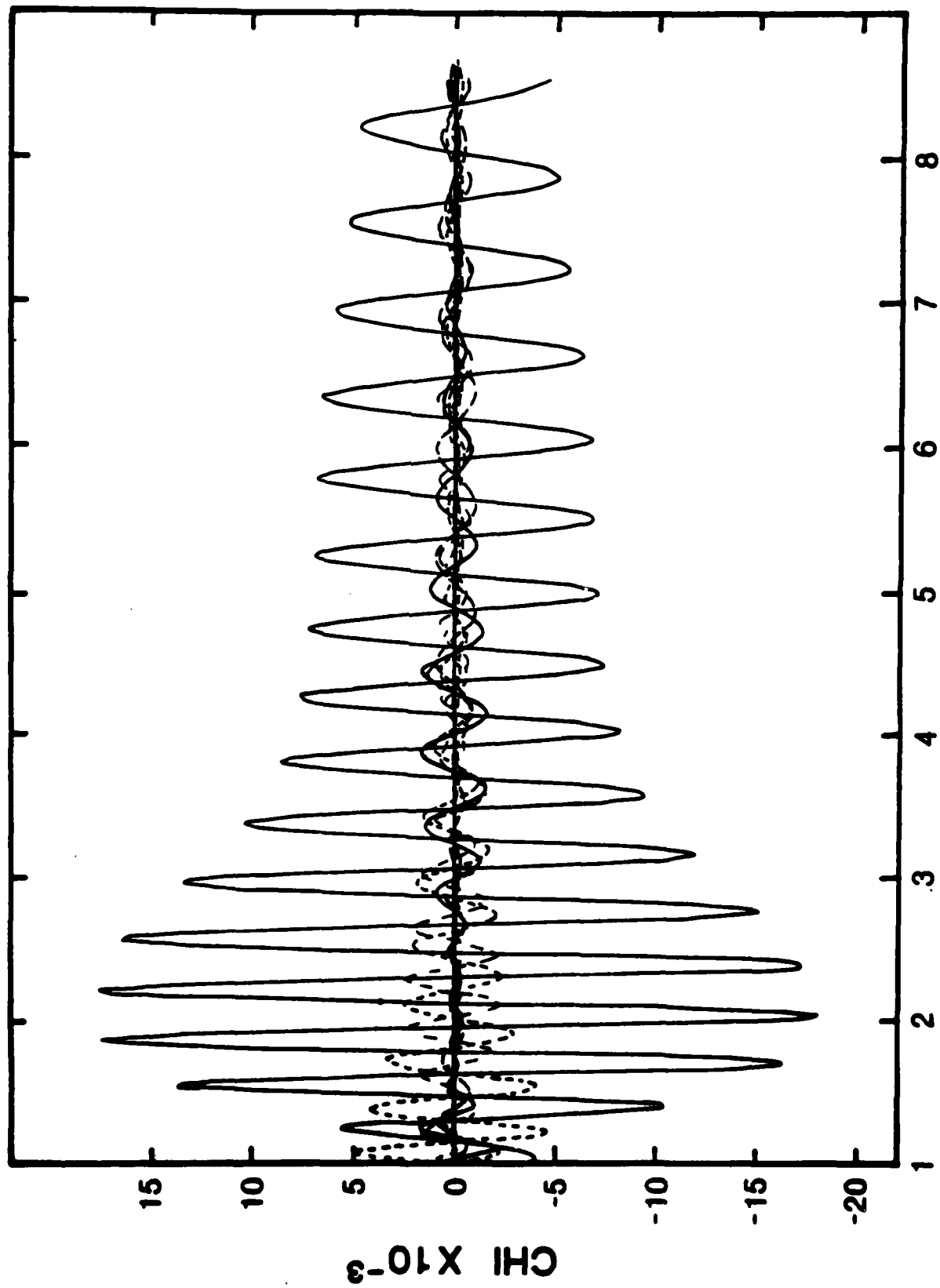
^c θ , the central angle, is defined to be the angle between radius vectors from the central atom to the two neighboring atoms in the three-atom problem (cf. Ref. 7).

Captions for Figures

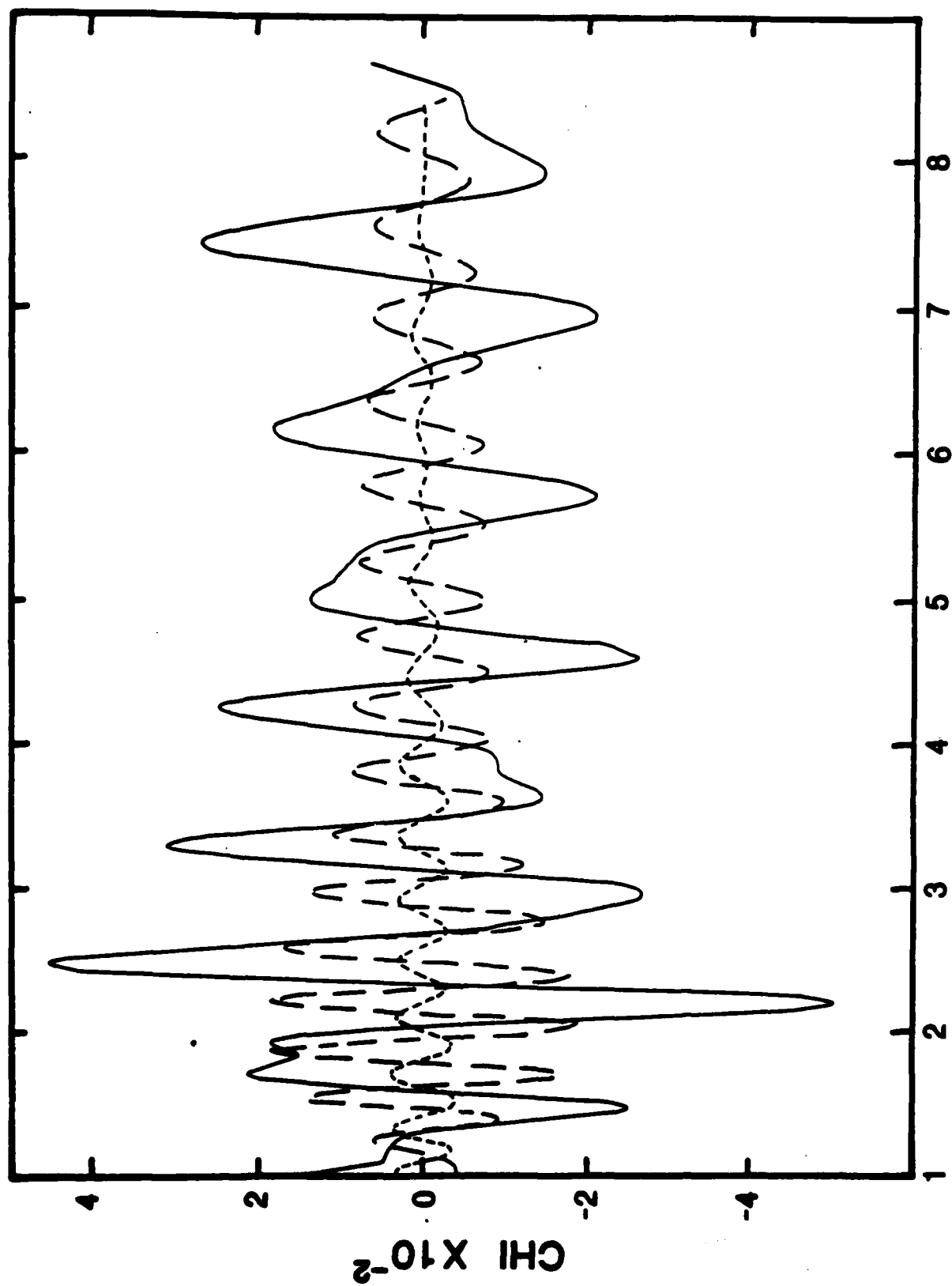
- FIG. 1. The scattering amplitude $F(\alpha, k)$ for different scattering angles: $0^\circ(\square)$, $60^\circ(\Delta)$, $90^\circ(\circ)$, $120^\circ(\circ)$, $150^\circ(\diamond)$, and $180^\circ(\nabla)$.
- FIG. 2. The scattering phase $\phi(\alpha, k)$ for different scattering angles: $0^\circ(\square)$, $60^\circ(\Delta)$, $90^\circ(\circ)$, $120^\circ(\circ)$, $150^\circ(\diamond)$, and $180^\circ(\nabla)$.
- FIG. 3. Calculated EXAFS spectra for different scattering paths: solid line corresponds to Ma path, the dashed lines correspond to the different double scattering paths.
- FIG. 4. Calculated EXAFS spectra: single scattering contributions (solid line), double scattering contributions (short dashed line), and the triple scattering contributions (long dashed line).
- FIG. 5. Comparison of Fourier-filtered experimental data (solid line) with calculated single scattering, EXAFS spectra (also Fourier-filtered) (dashed line). The radial distance in the filtering corresponds to (A) first, (B) second, (C) third, and (D) fourth shell.
- FIG. 6. Comparison of experimental EXAFS spectrum (solid lines) to (A) calculated single scattering involving the first three shells, (dashed line) and (B) sum of single, double and triple scattering contributions, including fourth shell (dashed line).
- FIG. 7. Experimental Pt L_{III} absorption edge (solid line) together with the fit (short dashed line) to the sum of the Lorentzian resonance (medium dashed line) and step functions (long dashed line).
- FIG. 8. Experimental Pt L_{III} absorption edge (solid line) together with the calculated spectra (dashed line).





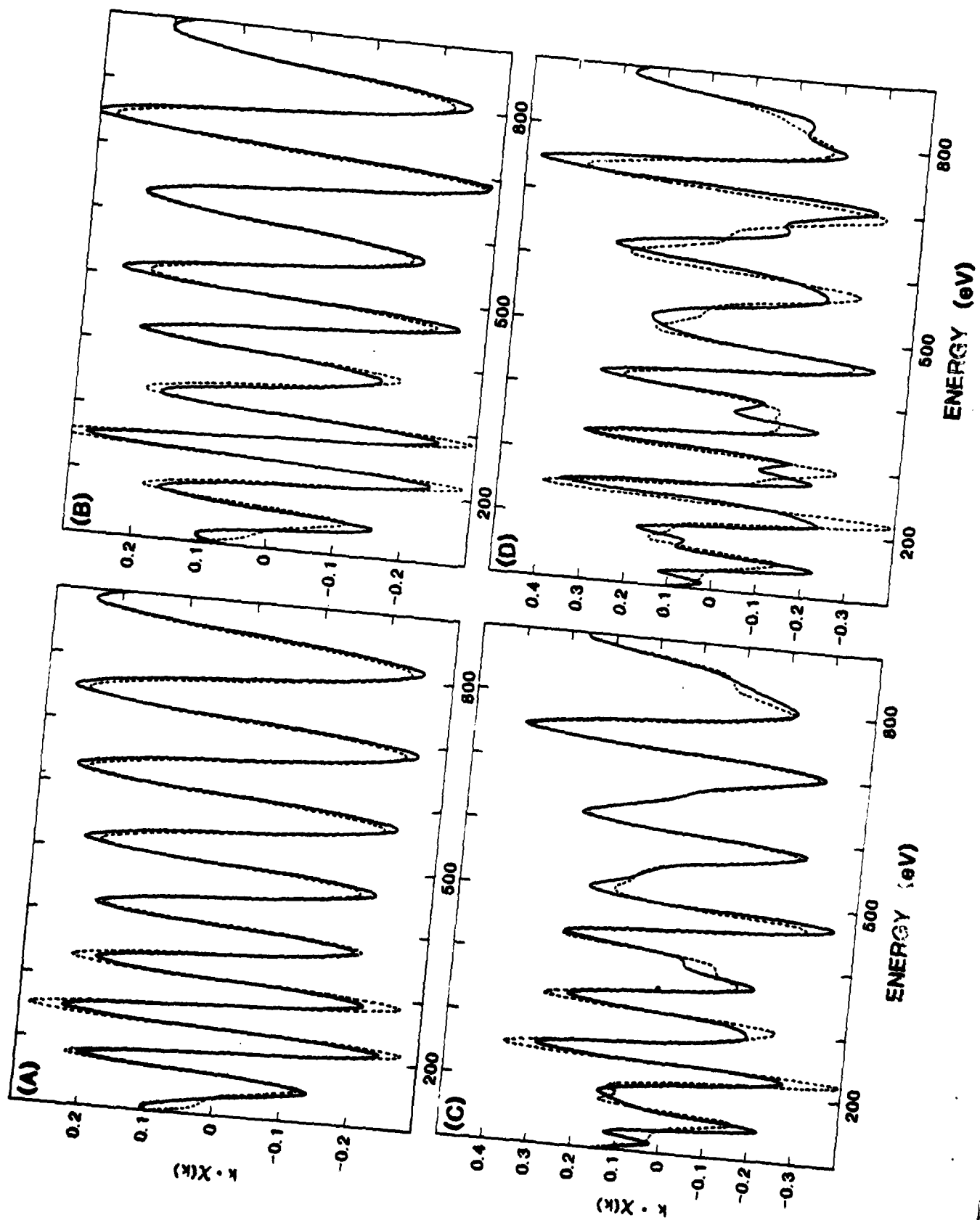


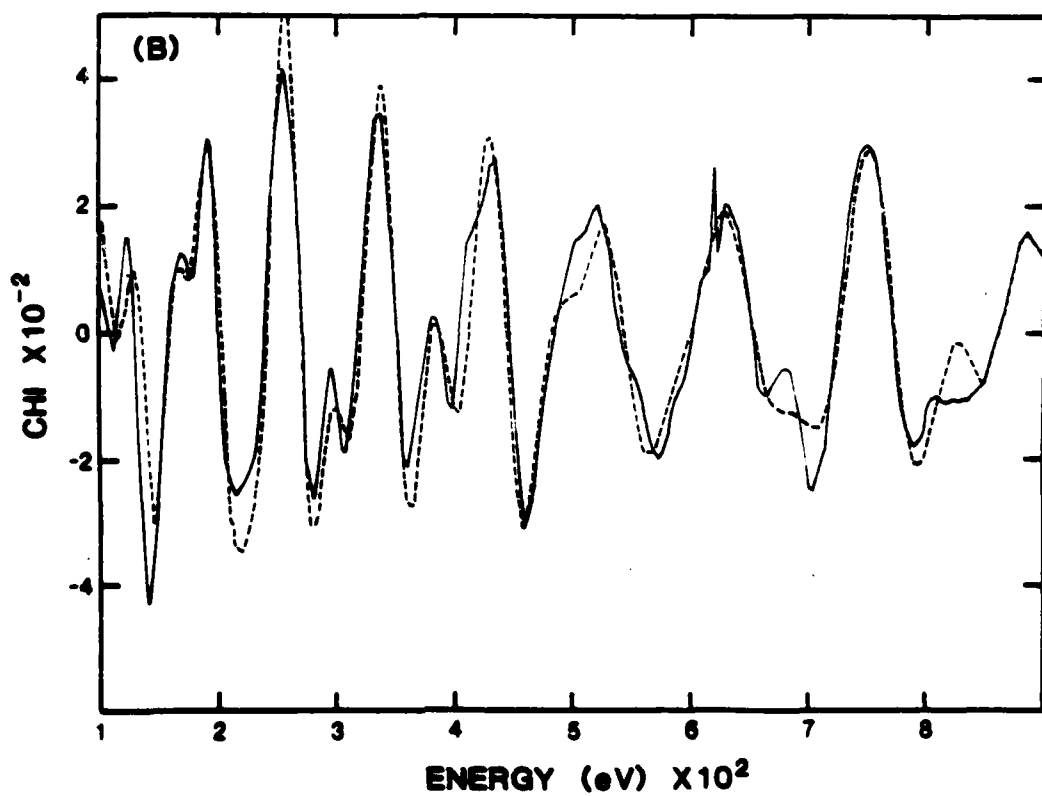
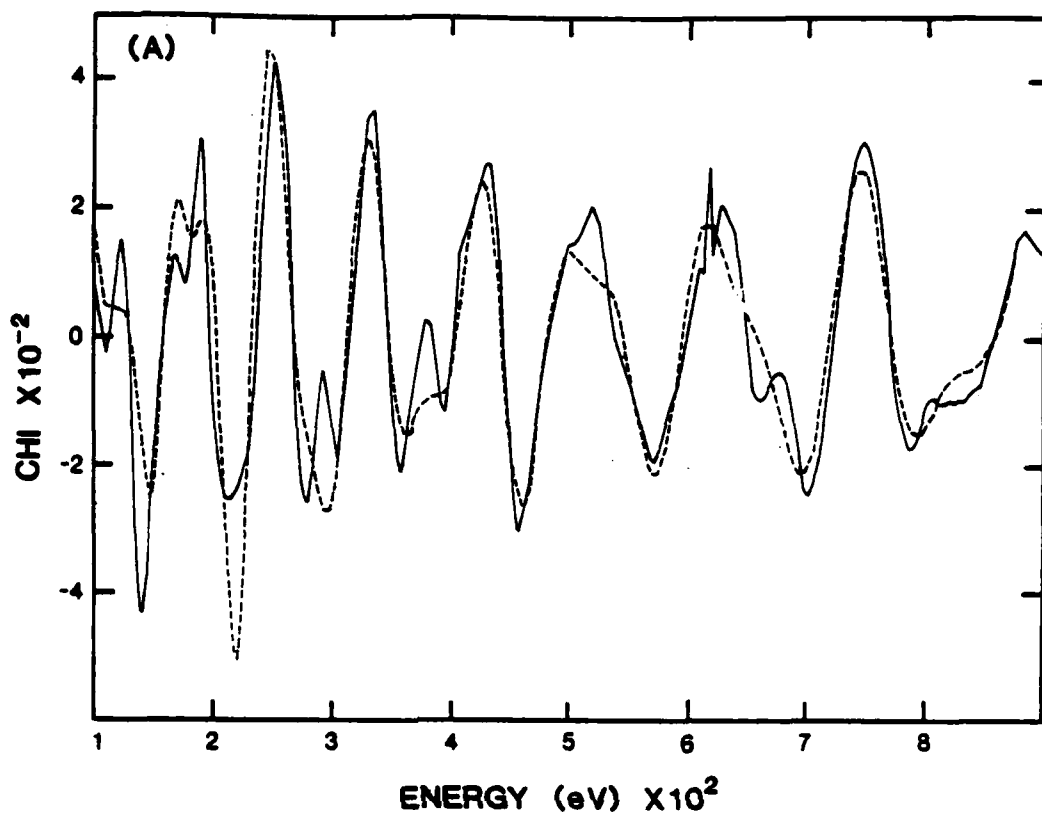
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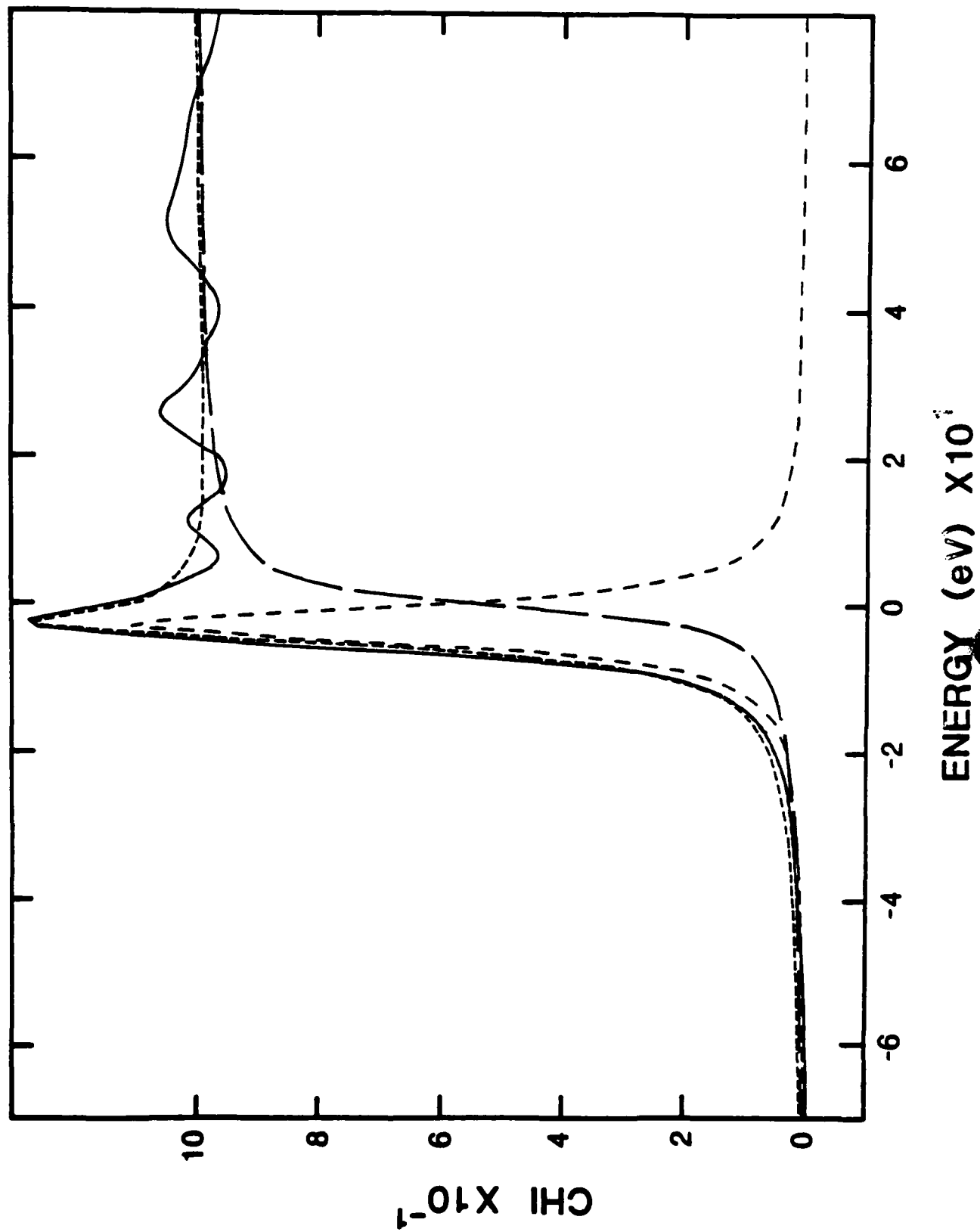


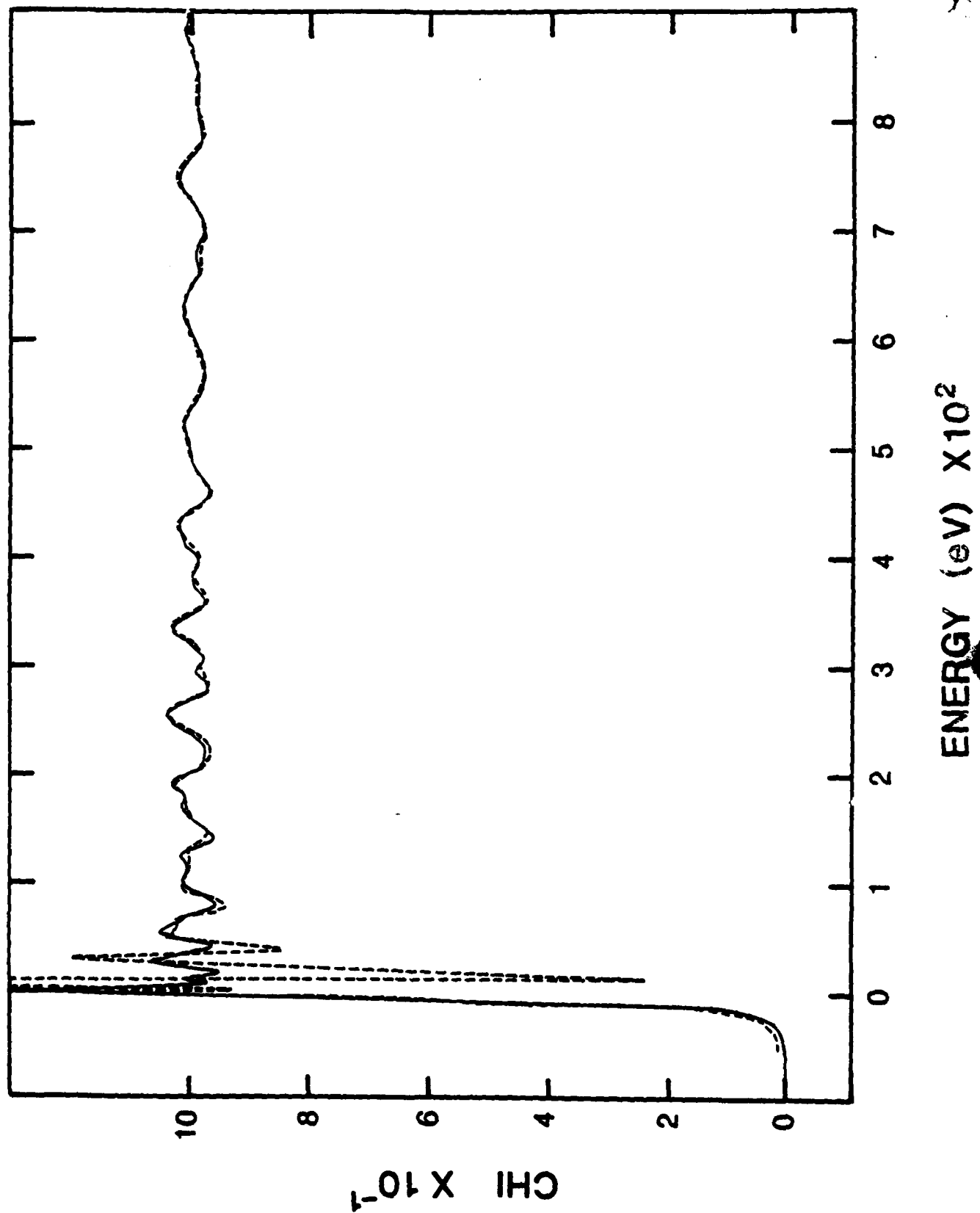
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